

IFW



POCKET NO.: 261137US6YAPCT/phh

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

RE APPLICATION OF:

Lee CHEN, et al.

SERIAL NO: 10/517,764

GROUP: 1763

FILED: December 23, 2004

EXAMINER: Allan W. OLSEN

FOR: ANISOTROPIC DRY ETCHING OF CU-CONTAINING LAYERS

LETTER

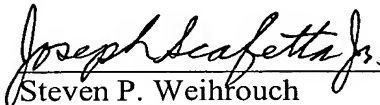
Mail Stop DD
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Submitted herewith is an International Preliminary Examination Report for the Examiner's consideration. The reference listed therein has been cited in the Office Action dated March 21, 2006.

Respectfully Submitted,

OBLON, SPIVAK, McCLELLAND,
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